



Japan Analytical Instruments Manufacturers' Association (JAIMA)

Japan Scientific Instruments Association (JSIA)

11 Items Certified during the Fourth Analytical and Scientific Instrument Heritage Certification

The Japan Analytical Instruments Manufacturers' Association (JAIMA; 1-12-3 Kanda Nishikicho, Chiyoda-ku, Tokyo 101-0054; chaired by Gon-emon Kurihara, president of JEOL Ltd.) and the Japan Scientific Instruments Association (JSIA; 3-8-5 Nihonbashi Honcho, Chuo-ku, Tokyo 103-0023; chaired by Hideto Yazawa, chairman of Dalton Co., Ltd.) have announced that 11 items have been certified during the fourth heritage certification program of analytical instruments and scientific equipment (20 items were certified during the first certification, 15 items during the second, and 16 during the third).

This certification program has been conducted yearly since 2012, when it was started by JAIMA and JSIA with the goal of passing along to future generations the important analytical instruments & techniques and scientific instruments that have contributed to the lives, economy, education, and culture of the Japanese people, as part of their cultural heritage. Since 2013, nominations have been received from a variety of sources in addition to members of both associations.

In this year's fourth certification, 11 items were selected from among 20 nominated items after strict examination by six experts (listed below) from industry, government, and academia. Each of the certified items was a world-renowned instrument or technology and can be viewed as a form of "scientific strength" that should be passed on to later generations.

At the Japan Analytical & Scientific Instruments Show (JASIS) 2015, an exhibition that will take place starting September 2 (Wed.) at Makuhari Messe, a certification ceremony will be held at a special event space, and the certified items will be on display within the exhibition venue for the duration of the exhibition. (URL: <http://www.jasis.jp/2015/>)

Selection Committee

Committee chairperson: Yoshimasa Nihei (Professor Emeritus at the University of Tokyo)

Committee members: Itaru Ishii (Honorary Fellow at the National Museum of Nature and Science, Tokyo)
Akira Ishitani (Advisor Emeritus of the Kanagawa Academy of Science and Technology)
Masaaki Kubota (Visiting Researcher at the National Institute of Advanced Industrial Science and Technology)

Keiichi Furuya (Professor Emeritus at the Tokyo University of Science)

Hiroo Yamasaki (Professor Emeritus at the University of Tokyo)

Selection Criteria

(1) A significant item in the history of the development of analytical and measurement technology & instruments (hereafter abbreviated as “analytical instruments”) and scientific technology & instruments (hereafter abbreviated as “scientific instruments”) that has significant value for future generations and meets the following criteria:

- a. Illustrates an important element or stage in the course of the development of related scientific technology & instruments
- b. Exhibits international uniqueness as an analytical or scientific instrument
- c. Has contributed to the creation of new analytical or scientific instruments

(2) An item that has had a prominent influence on the development and present state of the lives, industry, economy, society, and culture of the Japanese people and meets the following criteria:

- a. Has played a prominent role in the enhancement of the lives of the Japanese people
- b. Has contributed to the enhancement of Japan’s industrial and economic development and global standing
- c. Has made a significant contribution to the cohesion of society, culture, and scientific technology & instruments

Certified Item Categories

(1) Instruments that have been stored after use or collected and stored

(2) Documentation, samples, or both pertaining to technology or instruments

Analytical and Scientific Instrument Heritage Certification—Certified Item Names and Applicants

Certification No. 52

Name: Optical Microscope M & KATERA IV

Applicant: Sakura Finetek Japan Co., Ltd.

Certification No. 53

Name: Analytical Filter (Qualitative and Quantitative Filter Paper)

Applicant: Advantec Toyo Kaisha, Ltd.

Certification No. 54

Name: Honda's Thermobalance

Applicant: Tokyo Tech Museum and Archives

Certification No. 55

Name: Clinical Reagent Kit Shino-Test No. 1

Applicant: Shino-Test Corporation

Certification No. 56

Name: Development of Bowden typed Friction-Abrasion Analyzer

Applicant: Kyowa Interface Science Co., Ltd.

Certification No. 57

Name: Rapid Blood Analyzer RaBA-3010

Applicant: ARKRAY, Inc.

Certification No. 58

Name: Scanning Electron Microscope JSM-T20

Applicant: JEOL Ltd.

Certification No. 59

Name: Model 705 Hitachi Automatic Analyzer

Applicant: Hitachi High-Technologies Corporation

Certification No. 60

Name: High-Resolution pH Measurement System for Validating Standard Solutions Model COM-30 and Non-Leaking AgCl-type Reference Electrodes

Applicant: DKK-TOA Corporation

Certification No. 61

Name: Total Organic Carbon Analyzer TOC-500

Applicant: Shimadzu Corporation

Certification No. 62

Name: Riken Photoelectron Spectrometer/Surface Analyzer Model AC-1

Applicant: Riken Keiki Co., Ltd.

Inquiries

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For the detailed results of previous heritage certifications, please refer to the following webpage.

<http://www.jaima.or.jp/jp/heritage/>